

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Brendan Edward Allman et al. Art Unit : Unknown
Serial No. : Examiner : Unknown
Filed : August 17, 2006
Title : METHOD AND APPARATUS FOR PRODUCING AN IMAGE CONTAINING
DEPTH INFORMATION

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,



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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 20498-004US1	Application No.
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Brendan Edward Allman et al.	
		Filing Date August 17, 2006	Group Art Unit

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation Yes No
	AL	WO 00/26622	05/11/00	WIPO			
	AM	WO 03/034010	04/24/03	WIPO			
	AN						
	AO						
	AP						

Other Documents (Include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	Simon et al., "Estimation of Depth on Thick Edges from Sharp and Blurred Images", Proc. IEEE Instrumentation and Measurement Technology Conference, 2002, pp. 323-328
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	